IS218.015, ISSUE 2

INSPECTION REQUIREMENTS

RELAYS

235 TYPE

GENERAL EQUIPMENT REQUIREMENTS

COMMON SYSTEMS

TABLE 800-668-189

Lot Range	А	В	C	D	E	F	G	H	I	J				
Lot Size (total numbe relays in l	1 200	201 300	301 600	601 900	901 1200	1201 1500	1501 2000	2001 3000	3001 5000	5001 7000				
Sample Size (relays)	A11	180	260	300	340	370	400	440	500	560				
Inspection Item (note 2) (For requirements, refer to Section 040-242-701 and sections of Divi- sions 800.)	Basis For Counting	Allowable Defect Numbers												
	Defects	AN	AN	AN	AN	AN	AN	AN	AN	AN	AN			
l. Functional, Numerical, and Group Designations (on covers and on relays)	Record all defects found. See note 1.													
2. Relay Mounting	n	0	2	3	3	4	4	4	5	6	7			
3. Vertical Clearance	11	0	2	3	3	4	4	4	5	6	7			
4. Cover Spring and Cover Guide Pressure	83	0	5	3	3	4	4	4	5.	6	7			
5. Contact Alignment	12	0	2	3	3	4	4	4	5	6	7			
6. Contact Separation	n	0	2	3	3	4	4	4	5	6	7			
 Clearance Between Heater Unit Wrapping Wires and Adjacent Spring 	11	0	2	3	3	4	4	4	5	6	7			
8. Timing Requirements	п	0	3	5	5	6	7	8	9	10	11			
9. Relay Insulated From Mounting Plate	11	0	2	3	3	4	4	4	5	6	7			
AN = Allowable Number of defects	AN = Allowable Number of defects in sample.													

SPOTTINESS TABLE

Size of Subsample	3 25	26 70	71 125	126 175	176 200	201 250	251 300	301 350	351 400	401 450	451 500	501 550	551 600	601 650	651 700	701 750	751 800	801 850
SN	2	3	4	6	7	8	10	11	12	13	14	16	17	19	20	22	23	24
SN = Spottiness Number (applying to subsample).																		

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Note 1: For each type of defect recorded, sufficient additional inspection shall be made to insure the elimination of the irregularity in the equipment involved.

Note 2: Verification of this type of relay is notrequired except when test results or other evidence indicates an unsatisfactory condition of adjustment. For detailed explanation and use of tables, refer to Section 800-668-180.

REASONS FOR REISSUE

To reduce the sample size requirements based on the process average quality of the manufactured product and to revise note 2.